

Application No.	Applicant(s)	•
09/786,680	ONISHI ET AL.	
Examiner	Art Unit	
Cheukfan Lee	2622	

SEARCHED					
Class	Subclass	Date	Examiner		
358	482,483, 512-514	2/16/2005	C.L.		
	475,474				
	497,496				
	494,473				
	487,505				
	234-236				
	484, 509				
382	312,313				
	318,319				
250	208.1				
	234-236				
399	211				
359	209-212				

INT	INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner				
358	475,482	2/17/2005	C.L.				
	483						
	•						

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST search: (CIS (contact adj2 image adj sensor)), (scanning adj module), (scan\$5 head), (partition, divider)	2/16/2005	C.L.
EAST search (cont.): (light adj guid\$3), (optical adj2 guide) Intense Image search		·
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